

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/719,319	CHEN ET AL.	
Examiner	Art Unit	
Patricia L. Hailey	1755	

SEARCHED					
Class	Subclass	Date	Examiner		
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Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
search updated from prevoius action	9/7/2005	PLH		
Inventor search	9/6/2005	PLH		
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